L Number	Hits	Search Text	DB	Time stamp
-	56177	(test\$3) near (DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:54
-	23982	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:56
-	9894	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) ab. ((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).ti. ((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	918	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:57
-	93	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/725.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:59
-	149	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/731.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:58
-	464	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	240	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/734.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	354	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/736.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	454	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/02/16 16:59
-	66	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/741.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00
-	123	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/744.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00

	(272	(// /do 1 /do) (/DITE CITE CITE CITE		
-	6272	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:00
		"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	
		signals information input bit bits))).ab.	ЕРО, ЈРО,	
			DERWENT;	
			IBM_TDB	
-	1093	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:00
		"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	
		signals information input bit bits))) and ("operating system")	ЕРО; ЈРО,	
			DERWENT;	,
			IBM TDB	
_	20	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:01
	20	"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	2004/02/10 17.01
		signals information input bit bits) and (software simulation	EPO; JPO;	
		configuration))) and 714/744.ccls.		
		Configuration())) and 7147744.ccis.	DERWENT;	
•	10	(/A462	IBM_TDB	0004/00/16 15 01
-	12	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:01
		"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	
		signals information input bit bits) and (software simulation))) and	ЕРО; ЈРО;	
		714/744.ccls. ·	DERWENT;	
			IBM_TDB	
-	1040	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:02
		"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	
		signals information input bit bits) and (software simulation)))	ЕРО; ЈРО;	
			DERWENT;	
	,		IBM TDB	
_	2120	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:02
	2120	"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	2004/02/10/17.02
		signals information input bit bits) and (software simulation	EPO; JPO;	
		configuration)))	DERWENT;	
	445	((1 (42 1 (42) ((17) CITE CITE CITE CITE (1 (40 H 1) 1) 1)	IBM_TDB	
-	445	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:02
		"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB;	
		signals information input bit bits) and (software simulation) and (device	ЕРО; ЈРО;	
		driver)))	DERWENT;	
			IBM_TDB	
-	53	((test\$3 evaluat\$3) near ((DUT CUT SUT circuit\$2 "device under test"	USPAT;	2004/02/16 17:04
		"circuit under test" "system under test") and (data pattern patterns signal	US-PGPUB,	
		signals information input bit bits) and (software simulation) and	ЕРО; ЛРО;	
		(driver)))	DERWENT;	
			IBM_TDB	
-	1588	(test\$3 near (("semiconductor device" DUT CUT SUT circuit circuits	USPAT;	2004/02/16 17:06
		"device under test" "circuit under test" "system under test") and (data	US-PGPUB;	
,		pattern patterns signal signals information input bit bits)) and (software	ЕРО; ЛРО;	
		simulation) and driver)	DERWENT;	
			IBM TDB	
_	14	(test\$3 near (("semiconductor device" DUT CUT SUT circuit circuits	USPAT;	2004/02/16 17:07
	1.7	"device under test" "circuit under test" "system under test") and (data	US-PGPUB;	2007/02/10 17.07
		pattern patterns signal signals information input bit bits)) and (software		
	1		EPO; JPO;	
		simulation) and driver).clm.	DERWENT;	
	_	(4.402	IBM_TDB	
-	8	(test\$3 near (("semiconductor device" DUT CUT SUT circuit circuits	USPAT;	2004/02/16 17:09
:		"device under test" "circuit under test" "system under test") and (data	US-PGPUB;	
		pattern patterns signal signals information input bit bits)) and (software	ЕРО; ЈРО;	
		simulation) and driver).ab.	DERWENT;	
			IBM_TDB	
-	2	6578166.pn.	USPĀT;	2004/02/16 17:14
		_	US-PGPUB;	
			ЕРО; ЈРО;	
			DERWENT;	
			IBM_TDB	
	·	I	1	

-	. 2	6678643.pn.	USPAT;	2004/02/16 17:14
			US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	2	6591205.pn.	USPAT;	2004/02/16 17:12
			US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	2	5557559.pn.	USPAT;	2004/02/16 17:12
			US-PGPUB;	
1			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	2	5497378.pn.	USPAT;	2004/02/16 17:12
			US-PGPUB;	
			ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
	0	(6678643.pn. and 6678643.pn. and 6591205.pn. and 5557559.pn. and	USPĀT;	2004/02/16 17:19
		5497378.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT circuit\$2	US-PGPUB,	
		"device under test" "circuit under test" "system under test" data pattern	ЕРО; ЛРО;	
		patterns signal signals information input bit bits)	DERWENT;	
			IBM_TDB	
-	2	(6678643.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	USPĀT;	2004/02/16 17:18
		circuit\$2 "device under test" "circuit under test" "system under test" data	US-PGPUB;	
		pattern patterns signal signals information input bit bits)	ЕРО; ЛРО;	
		, r,	DERWENT;	
			IBM_TDB	
_	2	(5557559.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	USPAT;	2004/02/16 17:18
	_	circuit\$2 "device under test" "circuit under test" "system under test" data	US-PGPUB;	
		pattern patterns signal signals information input bit bits)	ЕРО; ЈРО;	
		Farmer and an arrangement and arrangement arrangement and arrangement	DERWENT;	
			IBM_TDB	
_	2	5497378.pn. and (test\$3 simulation evaluat\$3 DUT CUT SUT circuit\$2	USPAT;	2004/02/16 17:18
	_	"device under test" "circuit under test" "system under test" data pattern	US-PGPUB;	
		patterns signal signals information input bit bits)	ЕРО; ЛРО;	
		partition organic and an area of the property	DERWENT;	
	•		IBM_TDB	
_	2	(6591205.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	USPAT;	2004/02/16 17:18
	_	circuit\$2 "device under test" "circuit under test" "system under test" data	US-PGPUB;	200 11021110 111110
		pattern patterns signal signals information input bit bits)	ЕРО; ЛРО;	
		, , , , , , , , , , , , , , , , , , , ,	DERWENT;	
		· ·	IBM_TDB	
-	2	(6678643.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT	USPAT;	2004/02/16 17:18
	_	circuit\$2 "device under test" "circuit under test" "system under test" data	US-PGPUB;	
		pattern patterns signal signals information input bit bits)	ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	8	(6678643.pn. or 6678643.pn. or 6591205.pn. or 5557559.pn. or	USPAT;	2004/02/16 17:24
1 ,		5497378.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT circuit\$2	US-PGPUB;	
		"device under test" "circuit under test" "system under test" data pattern	ЕРО; ЛРО;	
		patterns signal signals information input bit bits)	DERWENT;	
			IBM_TDB	
-	8	(6678643.pn. or 6678643.pn. or 6591205.pn. or 5557559.pn. or	USPAT;	2004/02/16 17:24
	_	5497378.pn.) and (test\$3 simulation evaluat\$3 DUT CUT SUT circuit\$2	US-PGPUB;	
		"device under test" "circuit under test" "system under test" data pattern	ЕРО; ЛРО;	
		patterns signal signals information input bit bits driver)	DERWENT;	
			IBM_TDB	
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